

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1296	known near10 flaw\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 17:05
L2	898	known near5 flaw\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 17:05
L3	18	known near5 flaw\$3 same simulat\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 17:05
L4	10300	(716/3-6 703/13-17,22 714/715, 733-742,779,819-824).ccs.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:01
L5	6	known near5 flaw\$3 and L4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 17:07
L6	5	known near5 flaw\$3 and L4 and simulat\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 18:10
L14	30	model with (defect\$4 near3 (device or circuit)) same (IC or chip or (integrated adj circuit))	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:06
L15	1812	(built-in with test) same (IC or chip or (integrated adj circuit))	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:07
L16	458	simulat\$ and (built-in with test) same (IC or chip or (integrated adj circuit))	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:07
L17	119	simulat\$ and (built-in with test) same (IC or chip or (integrated adj circuit)) and (stuck near3 fault)	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:07
L18	45	simulat\$ and (built-in with test) same (IC or chip or (integrated adj circuit)) and (stuck near3 fault) and (detect\$4 same defect\$4)	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 18:08
L19	5	known near5 flaw\$3 adj3 (circuit or device) and simulat\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 18:13
L20	128	model\$4 with defect\$4 adj3 (circuit or device)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 18:13

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	"20050229121".pn. and flaw\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:12
S2	220	flaw\$3 and "716"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 09:38
S3	184	flaw\$3 and test\$4 and "716"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 09:38
S4	140	flaw\$3 and test\$4 and simulat\$5 and "716"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 09:39
S5	104	flaw\$3 and test\$4 and simulat\$5 and "716"/4-11.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 09:39
S6	52	flaw\$3 and test\$4 and simulat\$5 and "716"/4.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:26
S7	65476	(model\$4 with (defect\$4 or fault or fail)) or flaw\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:28
S8	58161	simulat\$4 same (model\$4 with (defect\$4 or fault or fail)) or flaw\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:28
S9	1449	simulat\$4 same ((model\$4 with (defect\$4 or fault or fail)) or flaw\$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:29
S10	601	simulat\$4 same test\$4 same ((model\$4 with (defect\$4 or fault or fail)) or flaw\$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:29
S11	20740	(determin\$4 or detect\$4) same ((model\$4 with (defect\$4 or fault or fail)) or flaw\$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:29
S12	373	S10 and S11	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:29
S13	59	S12 and 716/3-6.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 10:30
S14	74	model\$4 with (defect\$4) and test\$4 and simulat\$5 and flaw\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 09:22
S15	3	model\$4 with (defect\$4) and test\$4 and simulat\$5 and flaw\$4 and 716/3-6.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:06

S16	11	model\$4 with (defect\$4) and test\$4 and simulat\$5 and known same flaw\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:06
S17	9	("5228040" "5243538" "5257268" "5430736" "5475624" "5542043" "5724504" "5740086" "5831998").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/09 17:13
S18	23	("6141630").URPN.	USPAT	OR	ON	2006/01/09 17:15
S19	18	(known near5 flaw\$4) same simulat\$5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:22
S20	13	(known near5 flaw\$4) same simulat\$5 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:24
S21	3	(known near5 flaw\$4) and (model\$4 adj4 (fault or defect)) same simulat\$5 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:25
S22	384	(model\$4 adj4 (fault or defect)) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S23	278	(model\$4 adj4 (fault or defect)) same simulat\$5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S24	515	(model\$4 adj4 (fault or defect)) same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S25	142	S22 and S23	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S26	115	S24 and S25	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S27	25	S26 and 716/3-6.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/09 17:26
S28	6	flaw\$4 same (model\$4 with (defect\$4)) and test\$4 and simulat\$5	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 09:24
S29	101	simulat\$5 same flaw\$4 same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 10:55
S30	2806	(test\$4 or check\$4 or detect\$4 or inspect\$4 or verif\$7) same flaw\$4 same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 10:56
S31	73	S29 and S30	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 09:48

S32	27	S31 and model\$4 same (flaw\$4 or defect\$4 or fault\$4) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 09:50
S33	11	("4527249" "4703484" "4763289" "4764926" "4769817" "4901259" "4949341" "4961156" "5146460" "5177440" "5189365").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 10:53
S34	10300	(716/3-6 703/13-17,22 714/715, 733-742,779,819-824).cccls.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 10:55
S35	144	simulat\$5 same (flaw\$4 or (model\$4 near5 defect\$4)) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 10:56
S36	2946	(test\$4 or check\$4 or detect\$4 or inspect\$4 or verif\$7) same (flaw\$4 or (model\$4 near5 defect\$4)) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 10:57
S37	103	S35 and S36	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 10:57
S38	57	S34 and S37	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:47
S39	4411602	"7" and "10"	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:47
S40	10300	(716/3-6 703/13-17,22 714/715, 733-742,779,819-824).cccls.	US-PGPUB; USPAT; USOCR	OR	ON	2006/01/10 13:47
S41	144	simulat\$5 same (flaw\$4 or (model\$4 near5 defect\$4)) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:47
S42	2946	(test\$4 or check\$4 or detect\$4 or inspect\$4 or verif\$7) same (flaw\$4 or (model\$4 near5 defect\$4)) same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:47
S43	103	S41 and S42	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:47
S44	57	S40 and S43	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:52
S45	3	flaw near5 inject\$3 near5 function	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:53
S46	3	flaw same netlist same defect\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:54

S47	386	flaw same defect\$4 and simulat\$4 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:59
S48	12	S40 and S47	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 13:55
S49	50	flaw same defect\$4 and simulat\$4 and test\$4 and (model\$4 same defect\$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:01
S50	36	flaw same defect\$4 and simulat\$4 and test\$4 and (model\$4 same flaw)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:01
S51	1416	model same defect\$4 and simulat\$4 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:02
S52	287	detect\$4 same (model same defect\$4) and simulat\$4 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:02
S53	72	detect\$4 same (model same defect\$4) same simulat\$4 and test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:02
S54	42	detect\$4 same (model same defect\$4) same simulat\$4 same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:03
S55	173	(stuck near3 fault) same simulat\$4 same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:04
S56	82	(stuck near3 fault) same model\$4 same simulat\$4 same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:05
S57	217	(stuck near3 fault) same model\$4 same circuit	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:05
S58	82	(stuck near3 fault) same model\$4 same simulat\$ same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:05
S59	30	determin\$4 same (stuck near3 fault) same model\$4 same simulat\$ same test\$4	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:10
S60	20	S57 and S58 and S59	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:06
S61	182307	((determin\$4 or evaluat\$4) same ((stuck near3 fault) or model\$4 or flaw\$3)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:12
S62	41411	(simulat\$4) same ((stuck near3 fault) or model\$4 or flaw\$3)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:12

S63	202704	(test\$4 or verif\$7 or detect\$4 or discover\$4 or check\$4) same ((stuck near3 fault) or model\$4 or flaw\$3)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:13
S64	21	flaw\$3 same (model\$3 with defect\$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:13
S65	21107	S61 and S62	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:13
S66	13296	S63 and S65	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:14
S67	1522	S66 and S40	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:14
S68	2	S67 and S64	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 14:14
S69	1	"20050229121".pn. and simulat\$4 same test\$4 (model\$4 <i>accuracy</i>)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:23
S70	54	simulat\$3 same (flaw or (model\$4 near5 circuit near5 defect\$4)) same (IC or integrated adj2 circuit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:24
S71	1	(convert\$4 or translat\$4) same (test adj2 (data or vector)) same (flaw or (model\$4 near5 circuit near5 defect\$4)) same (IC or integrated adj2 circuit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:26
S72	11	(convert\$4 or translat\$4) same (test adj2 (data or vector)) and (flaw or (model\$4 near5 circuit near5 defect\$4)) same (IC or integrated adj2 circuit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:27
S73	82	(determin\$4 or evaluat\$4) same (flaw or (model\$4 near5 circuit near5 defect\$4)) same (IC or integrated adj2 circuit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:28
S74	1	S72 and S73	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:27
S75	231	(determin\$4 or evaluat\$4 or discover or detect\$4) same (flaw or (model\$4 near5 circuit near5 defect\$4)) same (IC or integrated adj2 circuit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:28
S76	2	S72 and S75	US-PGPUB; USPAT; EPO; JPO	OR	ON	2006/01/10 15:28